

Is Now Part of



ON Semiconductor®

To learn more about ON Semiconductor, please visit our website at www.onsemi.com

Please note: As part of the Fairchild Semiconductor integration, some of the Fairchild orderable part numbers will need to change in order to meet ON Semiconductor's system requirements. Since the ON Semiconductor product management systems do not have the ability to manage part nomenclature that utilizes an underscore (_), the underscore (_) in the Fairchild part numbers will be changed to a dash (-). This document may contain device numbers with an underscore (_). Please check the ON Semiconductor website to verify the updated device numbers. The most current and up-to-date ordering information can be found at www.onsemi.com. Please email any questions regarding the system integration to Fairchild <a href="general-regarding-numbers-n

ON Semiconductor and the ON Semiconductor logo are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdf/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor makes no warranty, representation or guarantee regarding the suitability of its products for any particular purpose, nor does ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any EDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officer



March 2015

FDD8882 / FDU8882 N-Channel PowerTrench® MOSFET 30V, 55A, 11.5m Ω

Features

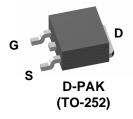
- $r_{DS(ON)} = 11.5 m\Omega$, $V_{GS} = 10 V$, $I_D = 35 A$
- $r_{DS(ON)} = 15m\Omega$, $V_{GS} = 4.5V$, $I_D = 35A$
- High performance trench technology for extremely low r_{DS(ON)}
- Low gate charge
- High power and current handling capability
- RoHS Complicant

Application

■ DC/DC converters

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{\mbox{\footnotesize{DS(ON)}}}$ and fast switching speed.







Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Ratings	Units
V _{DSS}	Drain to Source Voltage	30	V
V_{GS}	Gate to Source Voltage	±20	V
	Drain Current		
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$) (Note 1)	55	Α
I_D	Continuous (T _C = 25°C, V _{GS} = 4.5V) (Note 1)	50	Α
V _{GS} (1) (2) (3) (4) (4) (4) (4) (4) (4) (4) (4) (4) (4	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 52^{\circ}C/W$)	12.6	А
	Pulsed	Figure 4	А
E _{AS}	Single Pulse Avalanche Energy (Note 2)	41	mJ
	Power dissipation	55	W
FD	Derate above 25°C	0.37	W/°C
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-252, TO-251	2.73	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252, TO-251	100	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252, 1in ² copper pad area	52	°C/W

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8882	FDD8882	TO-252AA	13"	16mm	2500 units
FDU8882	FDU8882	TO-251AA	N/A (Tube)	N/A	75 units

Electrical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test Conditions		Min	Тур	Max	Units
Off Chara	acteristics						
B _{VDSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_0$	_{GS} = 0V	30	-	-	V
	Zero Gate Voltage Drain Current	V _{DS} = 24V		-	-	1	μΑ
DSS	Zero Gate Voltage Drain Gurrent	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA
		•		•	•	•	•

On Characteristics

V _{GS(TH)}	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = 250 \mu A$	1.2	-	2.5	V
r _{DS(ON)}	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 10V$	-	0.0094	0.0115	Ω
		$I_D = 35A, V_{GS} = 4.5V$	-	0.0130	0.0150	
		$I_D = 35A, V_{GS} = 10V,$ $T_J = 175^{\circ}C$	ı	0.0150	0.0190	

Dynami	c Characteristics						
C _{ISS}	Input Capacitance	V 45V V	$-V_{DS} = 15V, V_{GS} = 0V,$ -f = 1MHz		1260	-	pF
Coss	Output Capacitance				240	-	pF
C _{RSS}	Reverse Transfer Capacitance	1 - 1101112			140	-	pF
R _G	Gate Resistance	$V_{GS} = 0.5V, f = 1I$	MHz	-	2.4	-	Ω
Q _{g(TOT)}	Total Gate Charge at 10V	$V_{GS} = 0V \text{ to } 10V$		-	22	33	nC
Q _{g(5)}	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$	$V_{GS} = 0V \text{ to } 5V$ $V_{GS} = 0V \text{ to } 1V$ $I_{D} = 15V$ $I_{D} = 35A$ $I_{D} = 1.0 \text{mA}$	-	11.7	17.6	nC
$Q_{g(TH)}$	Threshold Gate Charge			-	1.2	1.8	nC
	Gate to Source Gate Charge			-	3.7	-	nC
Q _{gs} Q _{gs2}	Gate Charge Threshold to Plateau		.g = 1.511111	-	2.5	-	nC
Q _{gd}	Gate to Drain "Miller" Charge			-	4.6	-	nC

Switching Characteristics $(V_{GS} = 10V)$

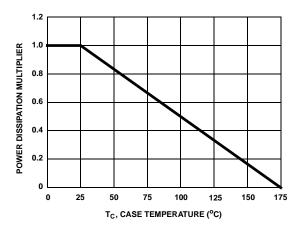
t _{ON}	Turn-On Time	$V_{DD} = 15V, I_{D} = 35A$ $V_{GS} = 10V, R_{GS} = 13\Omega$	-	-	135	ns
t _{d(ON)}	Turn-On Delay Time		-	8	-	ns
t _r	Rise Time		-	82	-	ns
t _{d(OFF)}	Turn-Off Delay Time		-	40	-	ns
t _f	Fall Time		-	25	-	ns
t _{OFF}	Turn-Off Time		-	-	98	ns

Drain-Source Diode Characteristics

V _{SD}	Source to Drain Diode Voltage	I _{SD} = 35A	-	-	1.25	V
		I _{SD} = 15A	-	-	1.0	V
t _{rr}	Reverse Recovery Time	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$	-	-	32	ns
Q _{RR}	Reverse Recovered Charge	$I_{SD} = 35A$, $dI_{SD}/dt = 100A/\mu s$	-	-	21	nC

- Notes: 1: Package current limitation is 35A. 2: Starting $T_J = 25^{\circ}C$, L = 0.1 mH, $I_{AS} = 28A$, $V_{DD} = 27V$, $V_{GS} = 10V$.





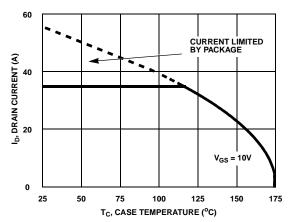


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

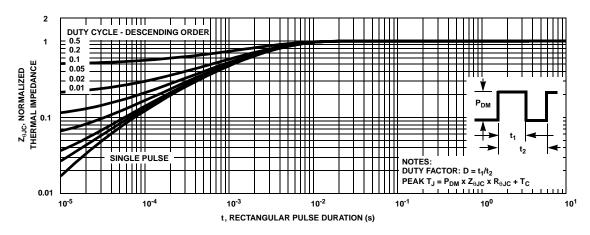


Figure 3. Normalized Maximum Transient Thermal Impedance

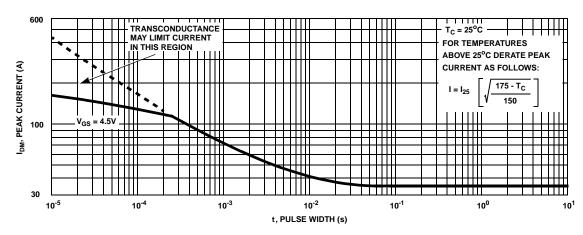
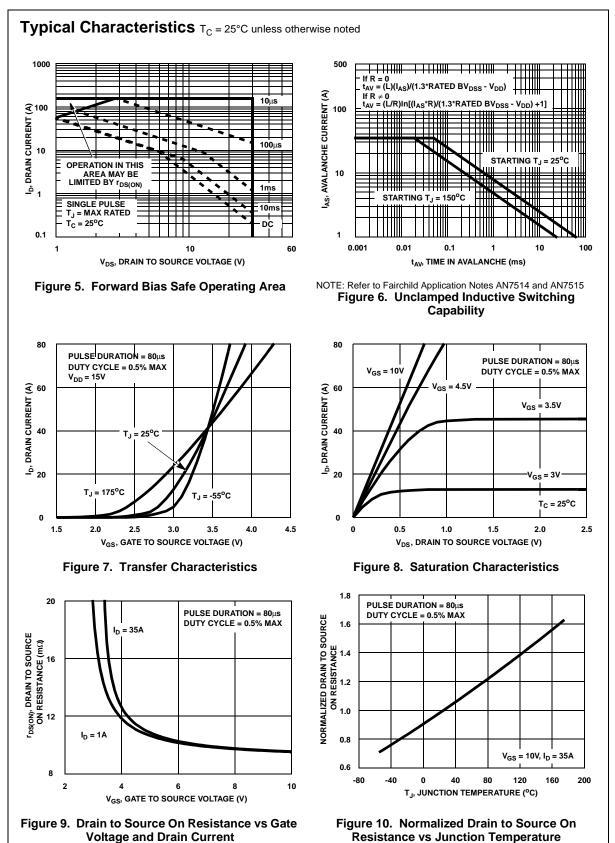


Figure 4. Peak Current Capability



Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

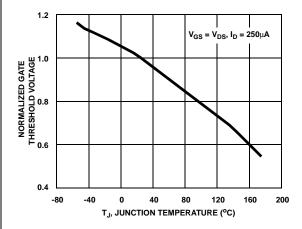


Figure 11. Normalized Gate Threshold Voltage vs
Junction Temperature

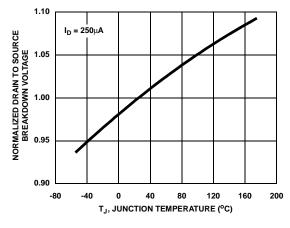


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

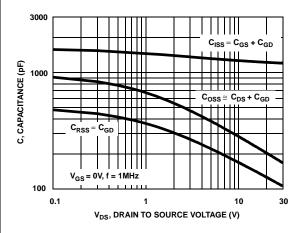


Figure 13. Capacitance vs Drain to Source Voltage

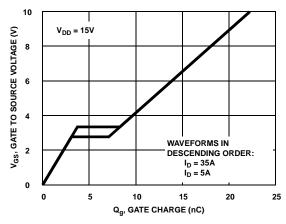


Figure 14. Gate Charge Waveforms for Constant Gate Current

Test Circuits and Waveforms

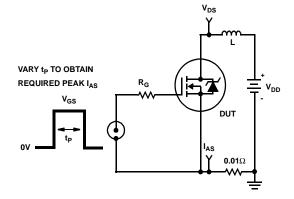


Figure 15. Unclamped Energy Test Circuit

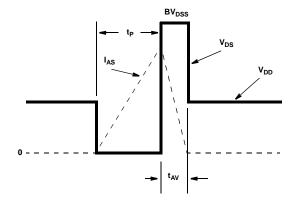


Figure 16. Unclamped Energy Waveforms

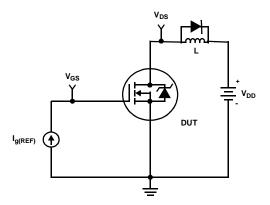


Figure 17. Gate Charge Test Circuit

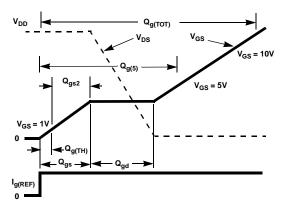


Figure 18. Gate Charge Waveforms

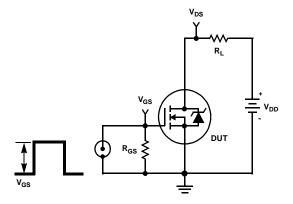


Figure 19. Switching Time Test Circuit

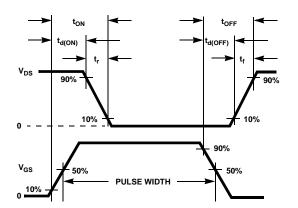


Figure 20. Switching Time Waveforms

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\Theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

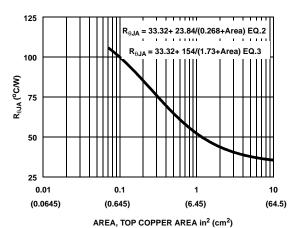
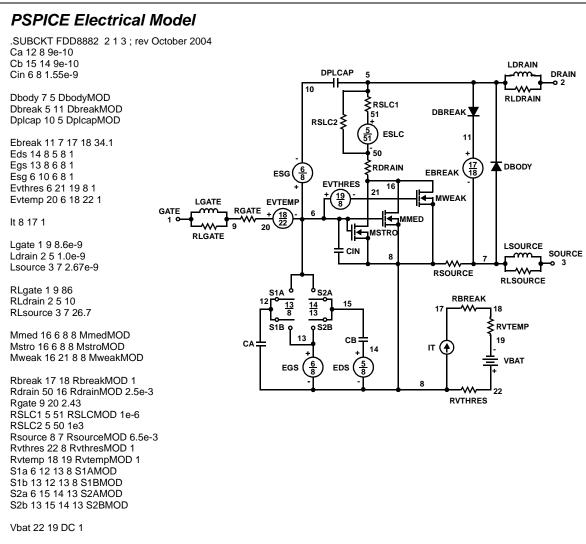


Figure 21. Thermal Resistance vs Mounting
Pad Area



ESLC 51 50 VALUE={(V(5,51)/ABS(V(5,51)))*(PWR(V(5,51)/(1e-6*600),10))}

.MODEL DbodyMOD D (IS=2E-12 IKF=10 N=1.01 RS=5.7e-3 TRS1=8e-4 TRS2=2e-7 + CJO=4.6e-10 M=0.58 TT=1e-11 XTI=2.7) .MODEL DbreakMOD D (RS=1 TRS1=1e-3 TRS2=-8.9e-6)

.MODEL DplcapMOD D (CJO=5.0e-10 IS=1e-30 N=10 M=0.45)

.MODEL MmedMOD NMOS (VTO=2.11 KP=14 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=2.43)

.MODEL MstroMOD NMOS (VTO=2.65 KP=240 IS=1e-30 N=10 TOX=1 L=1u W=1u)

.MODEL MweakMOD NMOS (VTO=1.82 KP=0.09 IS=1e-30 N=10 TOX=1 L=1u W=1u RG=24.3 RS=0.1)

.MODEL RbreakMOD RES (TC1=8.0e-4 TC2=-8e-7)

.MODEL RdrainMOD RES (TC1=-6e-3 TC2=6e-6)

.MODEL RSLCMOD RES (TC1=8e-5 TC2=2e-6)

.MODEL RsourceMOD RES (TC1=7.5e-3 TC2=1e-6) .MODEL RvthresMOD RES (TC1=-1.2e-3 TC2=-8.3e-6)

.MODEL RytempMOD RES (TC1=-2.5e-3 TC2=3.3e-7)

.MODEL S1AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-4 VOFF=-3.5)

.MODEL S1BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-3.5 VOFF=-4)

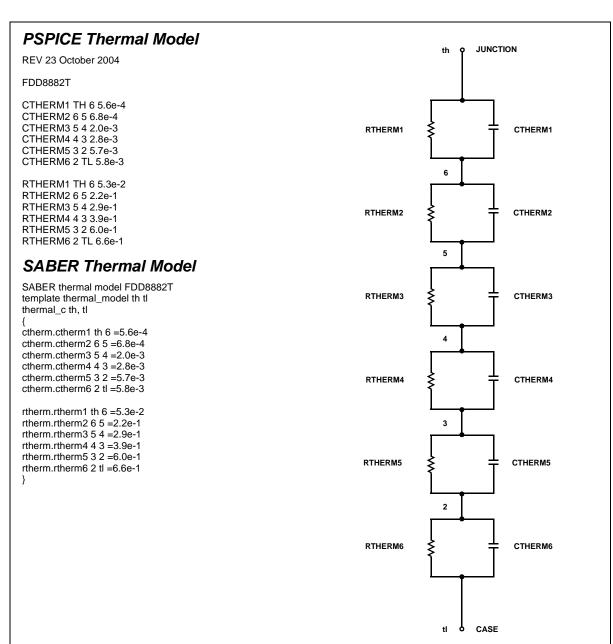
.MODEL S2AMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-2 VOFF=-1.5)

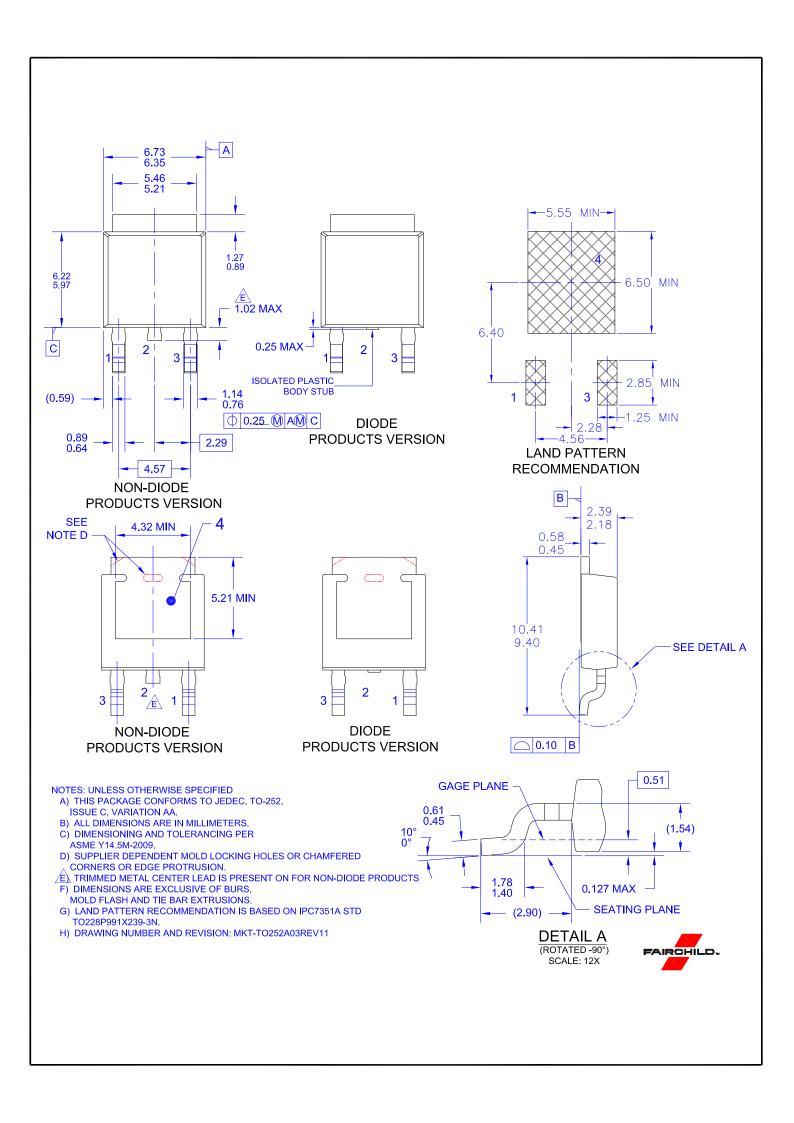
.MODEL S2BMOD VSWITCH (RON=1e-5 ROFF=0.1 VON=-1.5 VOFF=-2)

FNDS

Note: For further discussion of the PSPICE model, consult A New PSPICE Sub-Circuit for the Power MOSFET Featuring Global Temperature Options; IEEE Power Electronics Specialist Conference Records, 1991, written by William J. Hepp and C. Frank Wheatley

SABER Electrical Model rev October 2004 template FDD8882 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=2.0e-12,ikf=10,nl=1.01,rs=5.7e-3,trs1=8e-4,trs2=2e-7,cjo=4.6e-10,m=0.58,tt=1e-11,xti=2.7) dp..model dbreakmod = (rs=1,trs1=1e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=5.0e-10,isl=10e-30,nl=10,m=0.45) m..model mmedmod = (type=_n,vto=2.11,kp=14,is=1e-30, tox=1) m..model mstrongmod = (type=_n,vto=2.65,kp=240,is=1e-30, tox=1) m..model mweakmod = (type=_n,vto=1.82,kp=0.09,is=1e-30, tox=1,rs=0.1) sw_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-3.5) LDRAIN sw_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3.5,voff=-4) DPLCAP DRAIN sw_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2,voff=-1.5) 10 sw_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-1.5,voff=-2) RLDRAIN c.ca n12 n8 = 9e-10RSLC1 c.cb n15 n14 = 9e-10 51 RSLC2 ₹ c.cin n6 n8 = 1.1e-9ISCI dp.dbody n7 n5 = model=dbodymod DBREAK dp.dbreak n5 n11 = model=dbreakmod RDRAIN 8 dp.dplcap n10 n5 = model=dplcapmod **FSG** DBODY **EVTHRES** spe.ebreak n11 n7 n17 n18 = 34.1 (<u>19</u>) **MWEAK** LGATE **EVTEMP** spe.eds n14 n8 n5 n8 = 1 GATE ММЕD EBREA spe.egs n13 n8 n6 n8 = 1 spe.esg n6 n10 n6 n8 = 1 **←**MSTRC RLGATE spe.evthres n6 n21 n19 n8 = 1 LSOURCE spe.evtemp n20 n6 n18 n22 = 1 CIN SOURCE RSOURCE i.it n8 n17 = 1RLSOURCE I.lgate n1 n9 = 8.6e-9 RBREAK I.ldrain n2 n5 = 1.0e-9I.Isource n3 n7 = 2.67e-9**₹**RVTEMP S₁B oS2B 19 res.rlgate n1 n9 = 86 СА IT (♠ 14 res.rldrain n2 n5 = 10 VBAT res.rlsource n3 n7 = 26.7 **EGS EDS** m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u **RVTHRES** m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod. l=1u, w=1u res.rbreak n17 n18 = 1, tc1=8.0e-4,tc2=-8e-7 res.rdrain n50 n16 = 2.5e-3, tc1=-6e-3,tc2=6e-6 res.rgate n9 n20 = 2.43 res.rslc1 n5 n51 = 1e-6, tc1=8e-5,tc2=2e-6 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 6.5e-3, tc1=7.5e-3,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-1.2e-3,tc2=-8.3e-6res.rvtemp n18 n19 = 1. tc1=-2.5e-3.tc2=3.3e-7sw_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { (v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))*((abs(v(n5,n51)*1e6/600))**10))





ON Semiconductor and in are trademarks of Semiconductor Components Industries, LLC dba ON Semiconductor or its subsidiaries in the United States and/or other countries. ON Semiconductor owns the rights to a number of patents, trademarks, copyrights, trade secrets, and other intellectual property. A listing of ON Semiconductor's product/patent coverage may be accessed at www.onsemi.com/site/pdt/Patent-Marking.pdf. ON Semiconductor reserves the right to make changes without further notice to any products herein. ON Semiconductor assume any liability arising out of the application or use of any product or circuit, and specifically disclaims any and all liability, including without limitation special, consequential or incidental damages. Buyer is responsible for its products and applications using ON Semiconductor products, including compliance with all laws, regulations and safety requirements or standards, regardless of any support or applications information provided by ON Semiconductor. "Typical" parameters which may be provided in ON Semiconductor data sheets and/or specifications can and do vary in different applications and actual performance may vary over time. All operating parameters, including "Typicals" must be validated for each customer application by customer's technical experts. ON Semiconductor does not convey any license under its patent rights nor the rights of others. ON Semiconductor products are not designed, intended, or authorized for use as a critical component in life support systems or any FDA Class 3 medical devices or medical devices with a same or similar classification in a foreign jurisdiction or any devices intended for implantation in the human body. Should Buyer purchase or use ON Semiconductor products for any such unintended or unauthorized application, Buyer shall indemnify and hold ON Semiconductor and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and exp

PUBLICATION ORDERING INFORMATION

LITERATURE FULFILLMENT:

Literature Distribution Center for ON Semiconductor 19521 E. 32nd Pkwy, Aurora, Colorado 80011 USA Phone: 303-675-2175 or 800-344-3860 Toll Free USA/Canada Fax: 303-675-2176 or 800-344-3867 Toll Free USA/Canada Email: orderlit@onsemi.com N. American Technical Support: 800-282-9855 Toll Free USA/Canada
Europe, Middle East and Africa Technical Support:
Phone: 421 33 790 2910
Japan Customer Focus Center
Phone: 81-3-5817-1050

ON Semiconductor Website: www.onsemi.com

Order Literature: http://www.onsemi.com/orderlit

For additional information, please contact your local Sales Representative